



SCHOTTKY BIPOLAR LSI MICROCOMPUTER SET

3003 LOOK-AHEAD CARRY GENERATOR

The INTEL[®] Bipolar Microcomputer Set is a family of Schottky bipolar LSI circuits which simplify the construction of microprogrammed central processors and device controllers. These processors and controllers are truly microprogrammed in the sense that their control logic is organized around a separate read-only memory called the microprogram memory. Control signals for the various processing elements are generated by the microinstructions contained in the microprogram memory. In the implementation of a typical central processor, as shown below, the microprogram interprets a higher level of instructions called macroinstructions, similar to those found in a small computer. For device controllers, the microprograms directly implement the required control functions.

The INTEL[®] 3003 Look-Ahead Carry Generator (LCG) is a high speed circuit capable of anticipating a carry across a full 16-bit 3002 Central Processing Array. When used with a larger 3002 CP Array multiple 3003 carry generators provide high speed carry look-ahead capability for any word length.

The LCG accepts eight pairs of active high cascade inputs (X,Y) and an active low carry input and generates active low carries for up to eight groups of binary adders.

High Performance – 10 ns typical propagation delay

Compatible with INTEL 3001 MCU and 3002 CPE

DTL and TTL compatible

Full look-ahead across 8 adders

Low voltage diode input clamp

Expandable

28-pin DIP

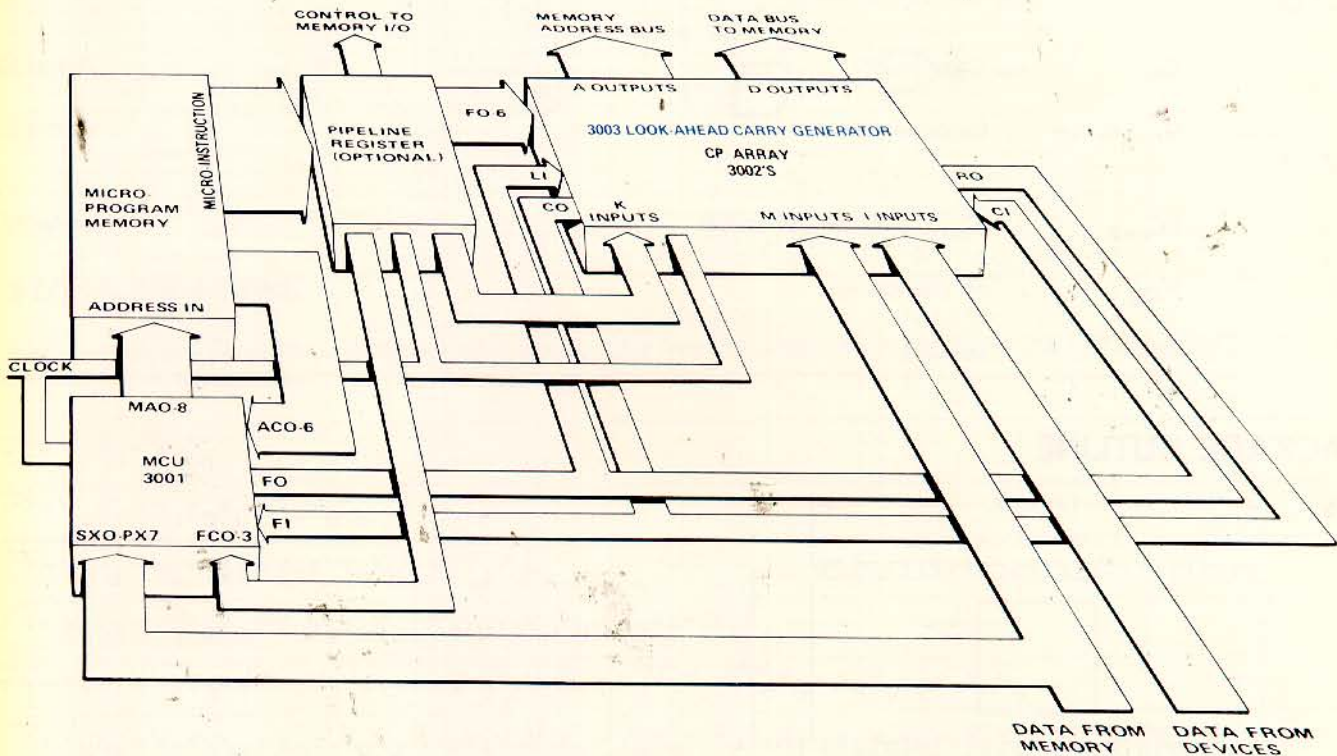


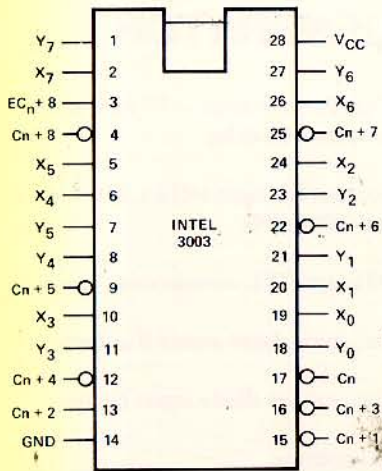
Diagram of a Typical System

Other members of the INTEL Bipolar Microcomputer Set:

3001 Microprogram Control Unit	3214 Priority Interrupt Control Unit	3304A Schottky Bipolar ROM (512 x 8)
3002 Central Processing Element	3226 Inverting Bi-Directional Bus Driver	3601 Schottky Bipolar PROM (256 x 4)
3212 Multi-Mode Latch Buffer	3301A Schottky Bipolar ROM (256 x 4)	3604 Schottky Bipolar PROM (512 x 8)

3003 LOOK-AHEAD CARRY GENERATOR

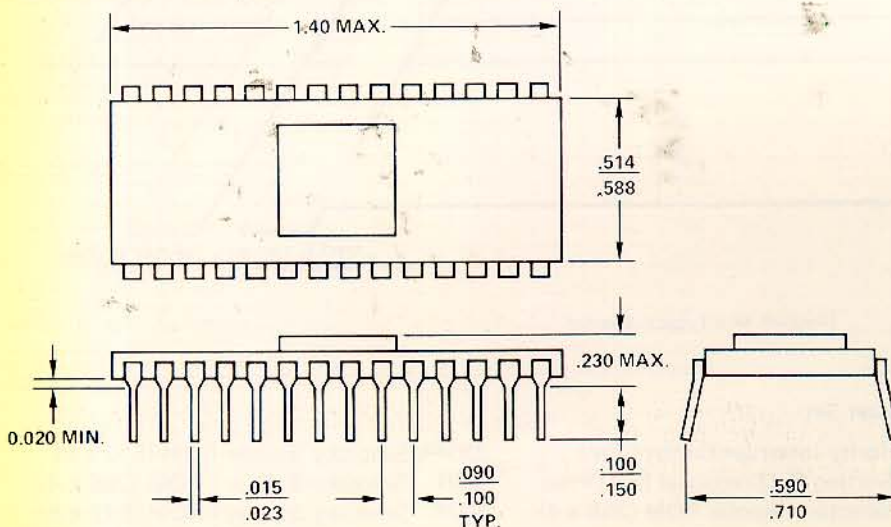
PACKAGE CONFIGURATION



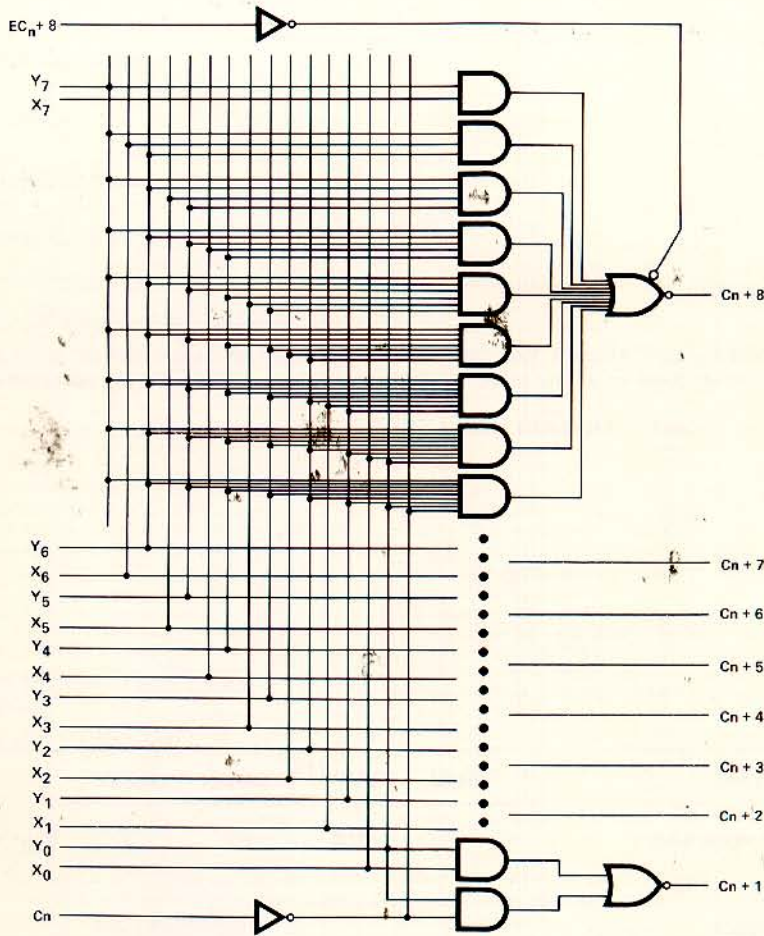
PIN DESCRIPTION

PIN	SYMBOL	NAME AND FUNCTION	TYPE
1,7,8,11,18 21,23,27	Y_0 - Y_7	Standard carry look-ahead inputs	Active HIGH
2,5,6,10,19 20,24,26	X_0 - X_7	Standard carry look-ahead inputs	Active HIGH
17	C_n	Carry input	Active LOW
4,9,12,13,15 16,22,25	C_{n+1} - C_{n+8}	Carry outputs	Active LOW
3	EC_{n+8}	C_{n+8} carry output enable	Active HIGH
28	V_{CC}	+5 volt supply	
14	GND	Ground	

PACKAGE OUTLINE



3003 LOGIC DIAGRAM



3003 LOGIC EQUATIONS

The 3003 Look-Ahead Generator is implemented in a compatible form for direct connection to the 3001 MCU and 3002 CPE. Logic equations for the 3003 are:

$$\overline{C_{n+1}} = Y_0 X_0 + Y_0 \overline{C_n}$$

$$\overline{C_{n+2}} = Y_1 X_1 + Y_1 Y_0 X_0 + Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+3}} = Y_2 X_2 + Y_2 Y_1 X_1 + Y_2 Y_1 Y_0 X_0 + Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+4}} = Y_3 X_3 + Y_3 Y_2 X_2 + Y_3 Y_2 Y_1 X_1 + Y_3 Y_2 Y_1 Y_0 X_0 + Y_3 Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+5}} = Y_4 X_4 + Y_4 Y_3 X_3 + Y_4 Y_3 Y_2 X_2 + Y_4 Y_3 Y_2 Y_1 X_1 + Y_4 Y_3 Y_2 Y_1 Y_0 X_0 + Y_4 Y_3 Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+6}} = Y_5 X_5 + Y_5 Y_4 X_4 + Y_5 Y_4 Y_3 X_3 + Y_5 Y_4 Y_3 Y_2 X_2 + Y_5 Y_4 Y_3 Y_2 Y_1 X_1 + Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 X_0 + Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+7}} = Y_6 X_6 + Y_6 Y_5 X_5 + Y_6 Y_5 Y_4 X_4 + Y_6 Y_5 Y_4 Y_3 X_3 + Y_6 Y_5 Y_4 Y_3 Y_2 X_2 + Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 X_1 + Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 X_0 + Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+8}} = \text{High Impedance State when } EC_{n+8} \text{ Low}$$

$$C_{n+8} = Y_7 X_7 + Y_7 Y_6 X_6 + Y_7 Y_6 Y_5 X_5 + Y_7 Y_6 Y_5 Y_4 X_4 + Y_7 Y_6 Y_5 Y_4 Y_3 X_3 + Y_7 Y_6 Y_5 Y_4 Y_3 Y_2 X_2 + Y_7 Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 X_1 + Y_7 Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 X_0 + Y_7 Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 \overline{C_n} \text{ when } EC_{n+8} \text{ high}$$

D.C. AND OPERATING CHARACTERISTICS

ABSOLUTE MAXIMUM RATINGS*

Temperature Under Bias	0°C to 70°C
Storage Temperature	-65°C to +160°C
All Output and Supply Voltages	-0.5V to +7V
All Input Voltages	-1.0V to +5.5V
Output Current	100 mA

*COMMENT: Stresses above those listed under "Absolute Maximum Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.

$T_A = 0^\circ\text{C to } +70^\circ\text{C}$

SYMBOL	PARAMETER	MIN.	TYP. ⁽¹⁾	MAX.	UNIT	CONDITIONS
V_C	Input Clamp Voltage (All Input Pins)		-0.8	-1.0	V	$V_{CC} = 4.75\text{V}, I_C = -5\text{ mA}$
I_F	Input Load Current: C_n and $EC_n + 8$ All Other Inputs		-0.07 -0.9	-0.25 -1.5	mA mA	$V_{CC} = 5.25\text{V}, V_F = 0.45\text{V}$
I_R	Input Leakage Current: C_n and $EC_n + 8$ All Other Inputs			40 100	μA μA	$V_{CC} = 5.25\text{V}, V_R = 5.25\text{V}$
V_{IL}	Input Low Voltage			0.8	V	$V_{CC} = 5.0\text{V}$
V_{IH}	Input High Voltage	2.0			V	$V_{CC} = 5.0\text{V}$
I_{CC}	Power Supply Current		80	130	mA	$V_{CC} = 5.25\text{V}$, All Y + $EC_n + 8$ high, All X + C_n low
V_{OL}	Output Low Voltage (All Output Pins)		0.35	0.45	V	$V_C = 4.75\text{V}, I_{OL} = 4\text{ mA}$
V_{OH}	Output High Voltage (All Output Pins)	2.4	3		V	$V_{CC} = 4.75\text{V}, I_{OH} = -1\text{ mA}$
I_{OS}	Short Circuit Output Current (All Output Pins)	-15	-40	-65	mA	$V_{CC} = 5\text{V}$
$I_{O(\text{off})}$	Off-State Output Current ($C_n + 8$)			-100 +100	μA μA	$V_{CC} = 5.25\text{V}, V_O = 0.45\text{V}$ $V_{CC} = 5.25\text{V}, V_O = 5.25\text{V}$

NOTE:

(1) Typical values are for $T_A = 25^\circ\text{C}$ and nominal supply voltage.

A.C. CHARACTERISTICS

$T_A = 0^\circ\text{C to } 70^\circ\text{C}$, $V_{CC} = +5\text{V} \pm 5\%$

SYMBOL	PARAMETER	MIN.	TYP. ⁽¹⁾	MAX.	UNIT
t_{XC}	X, Y to Outputs	3	10	20	ns
t_{CC}	Carry In to Outputs		13	30	ns
t_{EN}	Enable Time, $C_n + 8$		20	40	ns

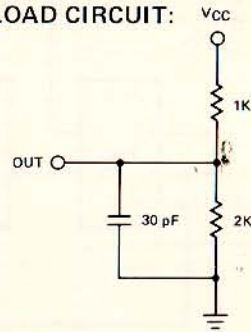
NOTE:

(1) Typical values are for $T_A = 25^\circ\text{C}$ and nominal supply voltage.

TEST CONDITIONS:

Input pulse amplitude of 2.5V.
 Input rise and fall times of 5 ns between 1 and 2 volts.
 Output loading is 5 mA and 30 pF.
 Speed measurements are made at 1.5 volt levels.

TEST LOAD CIRCUIT:



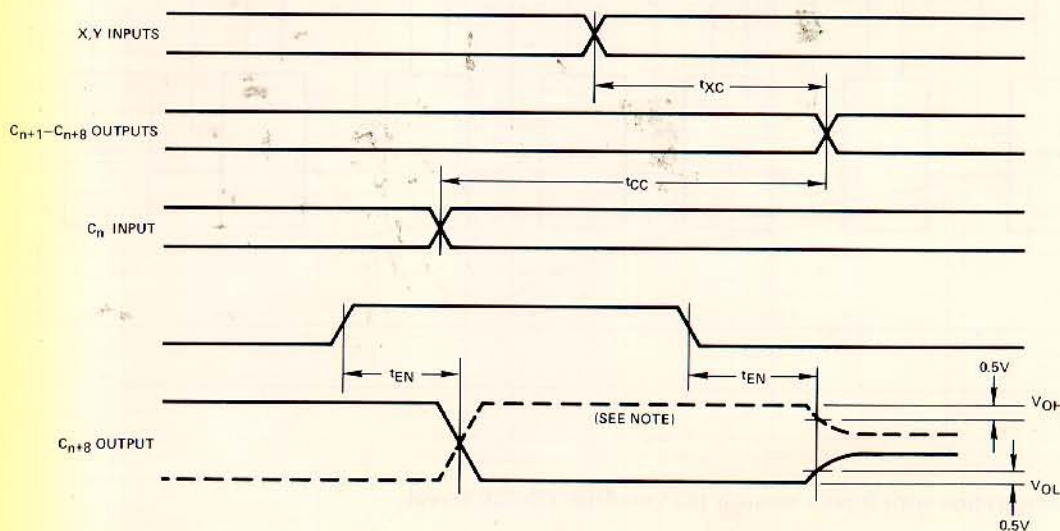
CAPACITANCE⁽²⁾ $T_A = 25^\circ\text{C}$

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
C_{IN}	Input Capacitance All inputs		12	20	pF
C_{OUT}	Output Capacitance $C_n + 8$		7	12	pF

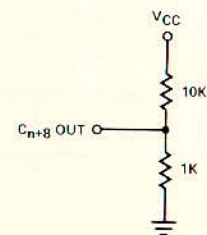
NOTE:

(2) This parameter is periodically sampled and is not 100% tested. Condition of measurement is $f = 1\text{ MHz}$, $V_{BIAS} = 5.0\text{V}$, $V_{CC} = 5.0\text{V}$ and $T_A = 25^\circ\text{C}$.

3003 WAVEFORMS



NOTE: ALTERNATE TEST LOAD:



3003 TYPICAL CONFIGURATIONS

The 3003 LCG can be directly tied to the 3001 MCU and a 3002 CP array of any word length. The following figures represent typical configurations of 16- and 32-bit CP arrays. Figures 1 and 2 illustrate use of the 3003 in a system where the carry output (CO) to the 3001 MCU is rippled through the high order CPE slice. Figure 3 illustrates use of the 3003 in a system where tri-state output C_{n+8} is connected directly to the flag input on the 3001 MCU. C_{n+8} is disabled during shift right by decoding that instruction externally, thus multiplexing C_{n+8} with the shift right (RO) output of the low order CPE slice.

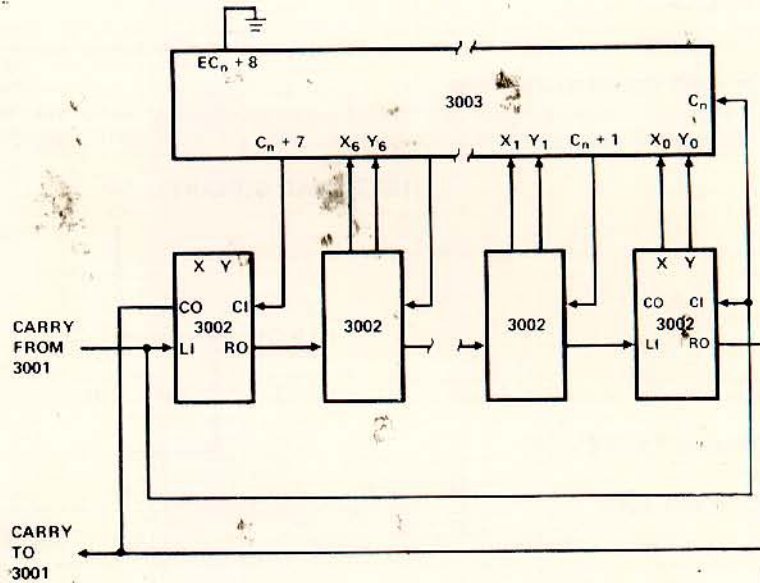


Figure 1. Carry Look-Ahead Configuration with Ripple through the Left Slice (16-Bit Array)

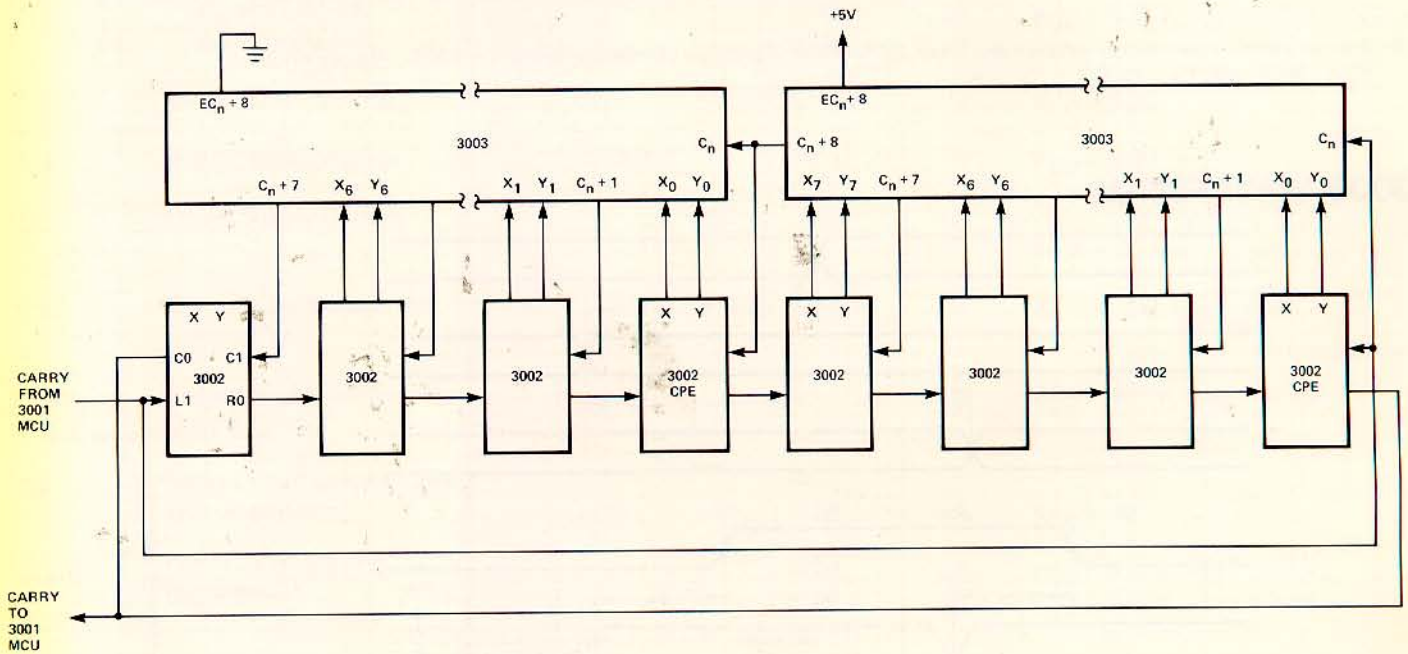
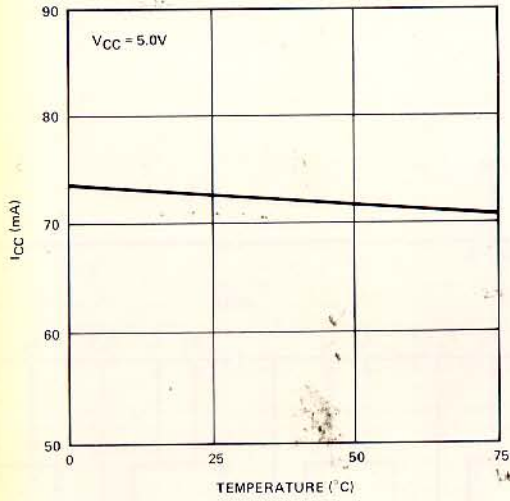


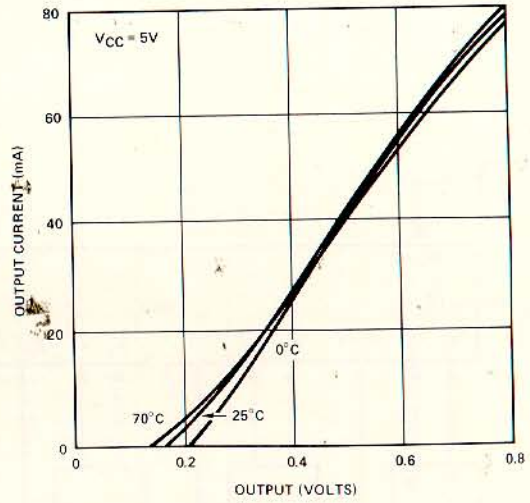
Figure 2. Carry Look-Ahead Configuration with Ripple through the Left Slice (32-Bit Array)

3003 TYPICAL A.C. AND D.C. CHARACTERISTICS

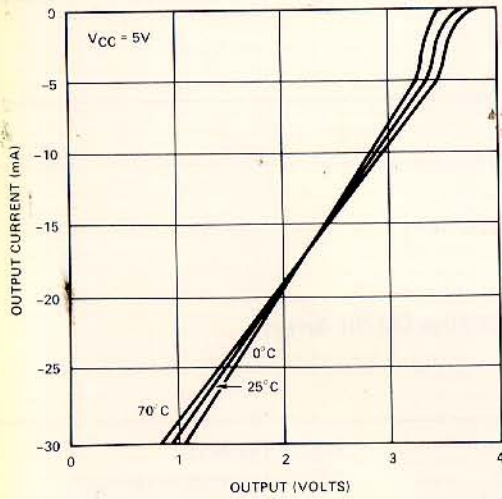
I_{CC} vs Temperature



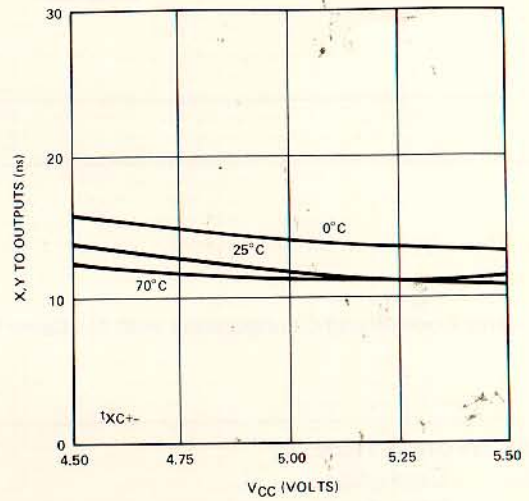
Output Current vs Output Low Voltage



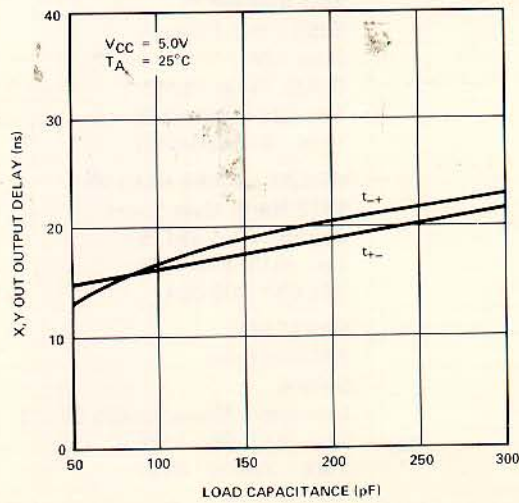
Output Current vs Output High Voltage



X,Y To Outputs vs V_{CC} & Temperature



X,Y To Output Delay vs Load Capacitance



3003 TYPICAL CONFIGURATIONS

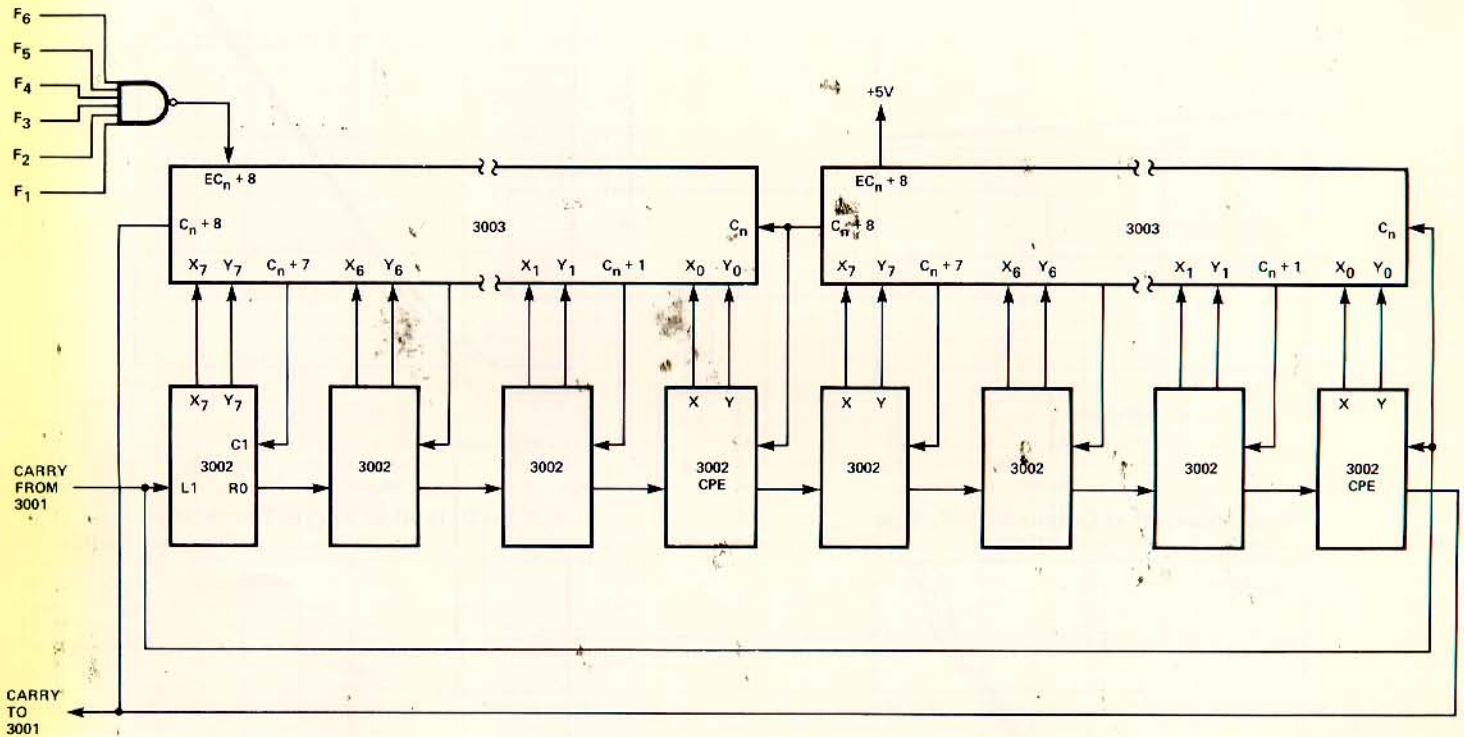


Figure 3. Carry Look-Ahead Configuration with No Carry Ripple through the Left Slice (32-Bit Array)

ORDERING INFORMATION

Part Number	Description
C3003	Look-Ahead Carry Generator



Intel Corporation
 3065 Bowers Avenue
 Santa Clara, California 95051
 Tel: (408) 246-7501
 TWX: 910-338-0026
 Telex: 34-6372

WESTERN

1651 East 4th Street
 Suite 228
 Santa Ana, California 92701
 Tel: (714) 835-9642
 TWX: 910-595-1114

MID-AMERICA

6350 L.B.J. Freeway
 Suite 178
 Dallas, Texas 75240
 Tel: (214) 661-8829
 TWX: 910-860-5487

GREAT LAKES REGION

8312 North Main Street
 Dayton, Ohio 45415
 Tel: (513) 890-5350
 TELEX: 288-004

EASTERN

2 Militia Drive
 Suite 4
 Lexington, Massachusetts 02173
 Tel: (617) 861-1136
 TWX: 710-321-0187

MID-ATLANTIC

520 Pennsylvania Avenue
 Suite 102
 Fort Washington, Pennsylvania 19034
 Tel: (215) 542-9444
 TWX: 510-661-3055

EUROPE

Belgium
 Intel Office
 216 Avenue Louise
 Brussels B 1050
 Tel: 649-20-03
 TELEX: 24814

ORIENT

Japan
 Intel Japan Corporation
 Kasahara Bldg.
 1-6-10, Uchikanda
 Chiyoda-ku
 Tokyo 101
 Tel: (03) 295-5441
 TELEX: 781-28426